









ISO1211, ISO1212

SLLSEY7B - JUNE 2017 - REVISED SEPTEMBER 2017

ISO121x Isolated 24-V to 60-V Digital Input Receivers for Digital Input Modules

Features 1

- Compliant to IEC 61131-2; Type 1, 2, 3 Characteristics
- Accurate Current Limit for Low-Power Dissipation:
 - 2.2 mA to 2.47 mA for Type 3
 - Adjustable up to 6.5 mA
- Eliminates the Need for Field-Side Power Supply
- High Input-Voltage Range With Reverse Polarity Protection: ±60 V
- Configurable as Sourcing or Sinking Input
- High Data Rates: Up to 4 Mbps
- High Transient Immunity: ±70-kV/µs CMTI
- Wide Supply Range (V_{CC1}): 2.25 V to 5.5 V
- Ambient Temperature Range: -40°C to +125°C
- **Compact Package Options:**
 - Single-Channel ISO1211, SOIC-8
 - Dual-Channel ISO1212, SSOP-16
- Safety-Related Certifications:
 - Basic Insulation per DIN V VDE V 0884-10
 - UL 1577 Recognition, 2500-V_{RMS} Insulation
 - CSA, CQC, TUV Certificates Available

Applications 2

- Programmable Logic Controller (PLC)
 - Digital Input Modules
 - Mixed I/O Modules
- Motor Drive I/O and Position Feedback
- CNC Control
- 48-V Systems
- Data Acquisition
- **Binary Input Modules**



Application Diagram

3 Description

The ISO1211 and ISO1212 devices are isolated 24-V to 60-V digital input receivers, compliant to IEC 61131-2 Type 1, 2, and 3 characteristics, suitable for programmable logic controllers (PLCs) and motorcontrol digital input modules. Unlike traditional optocoupler solutions with discrete, imprecise current limiting circuitry, the ISO121x devices provide a simple, low-power solution with an accurate current limit to enable the design of compact and highdensity I/O modules. These devices do not require field-side power supply and are configurable as sourcing or sinking inputs.

The ISO121x devices operate over the supply range of 2.25 V to 5.5 V, supporting 2.5-V, 3.3-V, and 5-V controllers. A ±60-V input tolerance with reverse polarity protection helps ensure the input pins are protected in case of faults with negligible reverse current. These devices support up to 4-Mbps data rates passing a minimum pulse width of 150 ns for high-speed operation. The ISO1211 device is ideal for designs that require channel-to-channel isolation and the ISO1212 device is ideal for multichannel space-constrained designs.

The ISO121x devices reduce component count, simplify system design, and reduce board temperatures compared to traditional solutions. For details, refer to the How To Simplify Isolated 24-V PLC Digital Input Module Designs TI TechNote.

Device Information ⁽¹⁾				
PART NUMBER	PACKAGE	BODY SIZE (NOM)		
ISO1211	SOIC (8)	4.90 mm × 3.91 mm		
ISO1212	SSOP (16)	4.90 mm × 3.90 mm		

(1) For all available packages, see the orderable addendum at the end of the data sheet.

ISO121x Devices Reduce Board Temperatures vs **Traditional Solutions**



a) 8-Ch With ISO1212

b) 8-Ch Traditional Solution Without Current Limit



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4 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

Changes from Revision A (September 2017) to Revision B

Changed the status from Advance Information to Production Data 1



5 Pin Configuration and Functions



Pin Functions

PIN		1/0	DESCRIPTION		
NO.	NAME	1/0	DESCRIPTION		
1	V _{CC1}	—	Power supply, side 1		
2	EN	I	Output enable. The output pin on side 1 is enabled when the EN pin is high or open. The output pin on side 1 is in the high-impedance state when the EN pin is low. In noisy applications, tie the EN pin to V_{CC1} .		
3	OUT	0	Channel output		
4	GND1	_	Ground connection for V _{CC1}		
5	SUB	_	Internal connection to input chip substrate. Leave this pin unconnected on the board.		
6	FGND	_	Field-side ground		
7	IN	I	Field-side current input		
8	SENSE	I	Field-side voltage sense		





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4	OUT1	0	Channel 1 output	
5	OUT2	0	Channel 2 output	
6	NC		Nationspeed	
7	NC		Not connected	
8	GND1	_	Ground connection for V _{CC1}	
9	FGND2	—	Field-side ground, channel 2	
10	IN2	I	Field-side current input, channel 2	
11	SENSE2	I	Field-side voltage sense, channel 2	
12	SUB2	—	Internal connection to input chip 2 substrate. Leave this pin unconnected on the board.	
13	SUB1	—	Internal connection to input chip 1 substrate. Leave this pin unconnected on the board.	
14	FGND1	—	Field-side ground, channel 1	
15	IN1	Ι	Field-side current input, channel 1	
16	SENSE1	I	Field-side voltage sense, channel 1	



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾

		MIN	MAX	UNIT
V _{CC1}	Supply voltage, control side	-0.5	6	V
V _{OUTx} , V _{EN}	Voltage on OUTx pins and EN pin	-0.5	$V_{CC1} + 0.5^{(2)}$	V
I _O	Output current on OUTx pins	-15	15	mA
V _{INx} , V _{SENSEx}	Voltage on IN and SENSE pins	-60	60	V
V _(ISO,FUNC)	Functional isolation between channels in ISO1212 on the field side	-60	60	V
TJ	Junction temperature	-40	150	°C
T _{stg}	Storage temperature	-65	150	°C

(1) Stresses beyond those listed under absolute maximum ratings may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under recommended operating conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) Maximum voltage must not exceed 6 V.

6.2 ESD Ratings

			VALUE	UNIT
V _(ESD)	Electrostatic	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	±2000	N/
	discharge	Charged device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	±1000	V

(1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

			MIN	MAX	UNIT
V _{CC1}	Supply voltage input side		2.25	5.5	V
V _{INx} , V _{SENSEx}	Voltage on INx and SENSEx pins ⁽¹⁾		-60	60	V
		$V_{CC1} = 5 V$	-4		
I _{OH}	High-level output current from OUTx pin	V _{CC1} = 3.3 V	-3		mA
		V _{CC1} = 2.5 V	-2		
		$V_{CC1} = 5 V$		4	
I _{OL}	Low-level output current into OUTx pin	V _{CC1} = 3.3 V		3	mA
		V _{CC1} = 2.5 V		2	
t _{UI}	Minimum pulse width at SENSEx pins		150		ns
T _A	Ambient temperature		-40	125	°C

(1) See the *Thermal Considerations* section.

ISO1211, ISO1212

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6.4 Thermal Information

		ISO1211	ISO1212	
	THERMAL METRIC ⁽¹⁾	D (SOIC)	DBQ (SSOP)	UNIT
		8 PINS	16 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	146.1	116.9	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	63.1	56.5	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	80	64.7	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	9.6	27.9	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	79	64.1	°C/W
R _{0JC(bot)}	Junction-to-case (bottom) thermal resistance	_	—	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

6.5 Power Ratings

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
ISO1	211					
P _D	Maximum power dissipation, both sides				450	mW
P _{D1}	Maximum power dissipation, output side (side 1)	V_{CC1} = 5.5 V, C_L = 15 pF, Input 2-MHz 50% duty- cycle square wave at SENSE pin, T_J = 150°C			20	mW
P_{D2}	Maximum power dissipation, field input side				430	mW
ISO1	212					
P _D	Maximum power dissipation, both sides				900	mW
P _{D1}	Maximum power dissipation, output side (side 1)	V_{CC1} = 5.5 V, C _L = 15 pF, Input 2-MHz 50% duty- cycle square wave at SENSEx pins, T _J = 150°C			40	mW
P _{D2}	Maximum power dissipation, field input side				860	mW

6.6 Insulation Specifications

	DADAMETED			SPECIFICATION		
	PARAMETER	TEST CONDITIONS	D-8	DBQ-16	UNIT	
CLR	External clearance ⁽¹⁾	Shortest terminal-to-terminal distance through air	4	3.7	mm	
CPG	External Creepage ⁽¹⁾	Shortest terminal-to-terminal distance across the package surface	4	3.7	μm	
DTI	Distance through the insulation	Minimum internal gap (internal clearance)	10.5	10.5	μm	
CTI	Comparative tracking index	DIN EN 60112 (VDE 0303-11); IEC 60112	> 600	> 600	V	
	Material Group	According to IEC 60664-1	I	I		
		Rated mains voltage ≤ 150 V _{RMS}	I-IV	I-IV		
	Overvoltage category	Rated mains voltage ≤ 300 V _{RMS}	1-111	1-111		
DIN V VC	DE V 0884-10 (VDE V 0884-10):2006-12	(2)				
V _{IORM}	Maximum repetitive peak isolation voltage	AC voltage (bipolar)	566	566	V _{PK}	
VIOWM	Maximum working isolation voltage	AC voltage (sine wave); time-dependent dielectric breakdown (TDDB) test	400	400	V _{RMS}	
1000	5 5	DC voltage	566	566	V _{DC}	
V _{IOTM}	Maximum transient isolation voltage	$V_{\text{TEST}} = V_{\text{IOTM}}$, t = 60 s (qualification), $V_{\text{TEST}} = V_{\text{IOTM}}$, t = 1 s (100% production)	3600	3600	V _{PK}	
V _{IOSM}	Maximum surge isolation voltage ⁽³⁾	Test method per IEC 60065-1, 1.2/50 μ s waveform, V _{TEST} = 1.3 × V _{IOSM} = 5200 V _{PK} (qualification)	4000	4000	V _{PK}	
		Method a: After I/O safety test subgroup 2/3, $V_{ini} = V_{IOTM}$, $t_{ini} = 60$ s; $V_{pd(m)} = 1.2 \times V_{IORM} = 680 V_{PK}$, $t_m = 10$ s	< 5	< 5		
q _{pd}	Apparent charge ⁽⁴⁾	Method a: After environmental tests subgroup 1, $V_{ini} = V_{IOTM}$, $t_{ini} = 60$ s; $V_{pd(m)} = 1.3 \times V_{IORM} = 736 V_{PK}$, $t_m = 10$ s	< 5	< 5	рС	
		Method b1: At routine test (100% production) and preconditioning (type test), $V_{ini} = V_{IOTM}$, $t_{ini} = 1$ s; $V_{pd(m)} = 1.5 \times V_{IORM} = 849 V_{PK}$, $t_m = 10$ s	< 5	< 5		
CIO	Barrier capacitance, input to output ⁽⁵⁾	$V_{IO} = 0.4 \times \sin (2 \pi ft), f = 1 MHz$	440	560	fF	
		$V_{IO} = 500 \text{ V}, \ T_A = 25^{\circ}\text{C}$	> 10 ¹²	> 10 ¹²		
R _{IO}	Insulation resistance, input to output ⁽⁵⁾	$V_{IO} = 500 \text{ V}, 100^{\circ}\text{C} \le T_A \le 125 ^{\circ}\text{C}$	> 10 ¹¹	> 10 ¹¹	Ω	
	ouput	$V_{IO} = 500 \text{ V} \text{ at } T_S = 150 \text{ °C}$	> 10 ⁹	> 10 ⁹		
	Pollution degree		2	2		
	Climatic category		40/125/21	40/125/21		
UL 1577						
V _{ISO}	Withstand isolation voltage	V_{TEST} = V_{ISO} = 2500 $V_{RMS},$ t = 60 s (qualification); V_{TEST} = 1.2 x V_{ISO} = 3000 $V_{RMS},$ t = 1 s (100% production)	2500	2500	V _{RMS}	

(1) Creepage and clearance requirements should be applied according to the specific equipment isolation standards of an application. Care should be taken to maintain the creepage and clearance distance of a board design to ensure that the mounting pads of the isolator on the printed-circuit board do not reduce this distance. Creepage and clearance on a printed-circuit board become equal in certain cases. Techniques such as inserting grooves and/or ribs on a printed circuit board are used to help increase these specifications.

(2) This coupler is suitable for *basic electrical insulation* only within the maximum operating ratings. Compliance with the safety ratings shall be ensured by means of suitable protective circuits.

(3) Testing is carried out in air or oil to determine the intrinsic surge immunity of the isolation barrier.

(4) Apparent charge is electrical discharge caused by a partial discharge (pd).

(5) All pins on each side of the barrier tied together creating a two-terminal device

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6.7 Safety-Related Certifications

VDE	CSA	UL	CQC	TUV
Certified according to DIN V VDE V 0884-10 (VDE V 0884-10):2006- 12 and DIN EN 61010-1 (VDE 0411-1):2011-07	Certified according to IEC 60950-1 and IEC 62368-1	Recognized under UL 1577 Component Recognition Program	Certified according to GB4943.1-2011	Certified according to EN 61010-1:2010 (3rd Ed) and EN 60950- 1:2006/A11:2009/A1:2010/ A12:2011/A2:2013
Basic Insulation, Maximum Transient Isolation Voltage, 3600 V_{PK} , Maximum Repetitive Peak Isolation Voltage, 566 V_{PK} , Maximum Surge Isolation Voltage, 4000 V_{PK}	370 V_{RMS} (ISO1212) and 400 V_{RMS} (ISO1211) Basic Insulation working voltage per CSA 60950-1-07+A1 + A2 and IEC 60950-1 2nd Ed. + A1 + A2 300 V_{RMS} Basic Insulation working voltage per CSA 62368-1-14 and IEC 62368- 1 2nd Ed.	Single protection, 2500 V _{RMS}	Basic Insulation, Altitude ≤ 5000m, Tropical Climate, 400 V _{RMS} maximum working voltage	Basic insulation per EN 61010-1:2010 (3rd Ed) up to working voltage of 300 V_{RMS} , Basic insulation per EN 60950- 1:2006/A11:2009/A1:2010/ A12:2011/A2:2013 up to working voltage of 370 V_{RMS} (ISO1212) and 400 V_{RMS} (ISO1211)
Certificate number: 40016131	Master contract number: 220991	File number: E181974	ISO1211 Certificate number: CQC15001121656, ISO1212 Certification Planned	Client ID number: 77311



6.8 Safety Limiting Values

Safety limiting⁽¹⁾ intends to minimize potential damage to the isolation barrier upon failure of input or output circuitry. A failure of the I/O can allow low resistance to ground or the supply and, without current limiting, dissipate sufficient power to overheat the die and damage the isolation barrier, potentially leading to secondary system failures.

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
ISO1211			1					
		$R_{\theta JA} = 146.1^{\circ}C/W, V_I = 2.75 V, T_J = 150^{\circ}C, T_A = 25^{\circ}C, \text{see Figure 1}$			310			
I _S	Safety input, output, or supply current - side 1	$R_{\theta JA} = 146.1^{\circ}C/W, V_I = 3.6 V, T_J = 150^{\circ}C, T_A = 25^{\circ}C, \text{see Figure 1}$			237	mA		
		$R_{\theta JA} = 146.1^{\circ}C/W, V_I = 5.5 V, T_J = 150^{\circ}C, T_A = 25^{\circ}C, \text{see Figure 1}$	155					
		$R_{\theta JA} = 146.1^{\circ}C/W, V_I = 24 V, T_J = 150^{\circ}C, T_A = 25^{\circ}C, see Figure 1$			35			
I _S Safety input c	Safety input current - field side	$R_{\theta JA} = 146.1^{\circ}C/W, V_I = 36 V, T_J = 150^{\circ}C, T_A = 25^{\circ}C, \text{see Figure 1}$		23				
		$R_{\theta JA} = 146.1^{\circ}C/W, V_I = 60 V, T_J = 150^{\circ}C, T_A = 25^{\circ}C, see Figure 1$						
Ps	Safety input, output, or total power	$R_{\theta JA} = 146.1^{\circ}C/W$, $T_J = 150^{\circ}C$, $T_A = 25^{\circ}C$, see Figure 2			855	mW		
T _S	Maximum safety temperature				150	°C		
ISO1212								
		$R_{\theta JA} = 116.9^{\circ}C/W, V_{I} = 2.75 V, T_{J} = 150^{\circ}C, T_{A} = 25^{\circ}C, \text{ see Figure 3}$	389					
I _S	Safety input, output, or supply current - side 1	$R_{\theta JA}$ = 116.9°C/W, V _I = 3.6 V, T _J = 150°C, T _A = 25°C, see Figure 3		297	mA			
		$R_{\theta JA} = 116.9^{\circ}C/W, V_I = 5.5 V, T_J = 150^{\circ}C, T_A = 25^{\circ}C, \text{see Figure 3}$			194			
		$\label{eq:R_bJA} \begin{array}{l} R_{\thetaJA} = 116.9^\circ\text{C/W}, \ V_I = 24 \ V, \ T_J = 150^\circ\text{C}, \\ T_A = 25^\circ\text{C}, \ \text{see Figure 3} \end{array}$			44			
I _S	Safety input current - field side	$\label{eq:RbJA} \begin{array}{l} R_{\text{bJA}}\text{=} \ 116.9^{\circ}\text{C/W}, \ V_{\text{I}} = 36 \ V, \ T_{\text{J}} = 150^{\circ}\text{C}, \\ T_{\text{A}} = 25^{\circ}\text{C}, \ \text{see Figure 3} \end{array}$	V, T _J = 150°C,					
		$\label{eq:RbJA} \begin{array}{l} R_{\text{bJA}} = 116.9^{\circ}\text{C/W}, \ V_{I} = 60 \ V, \ T_{J} = 150^{\circ}\text{C}, \\ T_{A} = 25^{\circ}\text{C}, \ \text{see Figure 3} \end{array}$						
Ps	Safety input, output, or total power	$R_{\theta JA} = 116.9^{\circ}C/W$, $T_J = 150^{\circ}C$, $T_A = 25^{\circ}C$, see Figure 4			1070	mW		
T _S	Maximum safety temperature				150	°C		

(1) The safety-limiting constraint is the maximum junction temperature specified in the data sheet. The power dissipation and junction-to-air thermal impedance of the device installed in the application hardware determines the junction temperature. The assumed junction-to-air thermal resistance in the *Thermal Information* table is that of a device installed on a high-K test board for leaded surface-mount packages. The power is the recommended maximum input voltage times the current. The junction temperature is then the ambient temperature plus the power times the junction-to-air thermal resistance.

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TEXAS INSTRUMENTS

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6.9 Electrical Characteristics—DC Specification

(Over recommended operating conditions unless otherwise noted).

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{CC1} VOLTA	GE SUPPLY						
V _{IT+ (UVLO1)}	Positive-going UVLO t (V _{CC1})	hreshold voltage				2.25	V
V _{IT- (UVLO1)}	Negative-going UVLO	threshold (V _{CC1})		1.7			V
V _{HYS (UVLO1)}	UVLO threshold hyster	resis (V _{CC1})			0.2		V
laa	V _{CC1} supply	ISO1211	EN - Vee		0.6	1	mΑ
ICC1	quiescent current	ISO1212			1.2	1.9	
LOGIC I/O			1				
V _{IT+ (EN)}	Positive-going input log voltage for EN pin	gic threshold				0.7 × V _{CC1}	V
V _{IT- (EN)}	Negative-going input lo voltage for EN pin	ogic threshold		0.3 × V _{CC1}			V
V _{HYS(EN)}	Input hysteresis voltag	e for EN pin			0.1 × V _{CC1}		V
I _{IH}	Low-level input leakag	e at EN pin	EN = GND1	-10			μA
V _{OH}	High-level output voltage on OUTx		$ \begin{array}{l} V_{CC1} = 4.5 \; V; \; I_{OH} = -4 \; mA \\ V_{CC1} = 3 \; V; \; I_{OH} = -3 \; mA \\ V_{CC1} = 2.25 \; V; \; I_{OH} = -2 \; mA, \; see \; Figure \; 10 \end{array} $	V _{CC1} - 0.4			V
V _{OL}	Low-level output voltage on OUTx					0.4	V
CURRENT L	.IMIT						
I _(INx+SENSEx) , TYP	Typical sum of current and SENSE pins acros	drawn from IN ss temperature	$ \begin{array}{l} R_{THR} = 0 \; \Omega, \; R_{SENSE} = 562 \; \Omega, \; V_{SENSE} = 24 \; V, \\ -40^\circ C < T_A < 125^\circ C, \; see \ Figure \ 11 \end{array} $	2.2		2.47	mA
			$ \begin{array}{l} R_{THR} = 0 \; \Omega, \; R_{SENSE} = 562 \; \Omega \pm 1\%; \\ -60 \; V < V_{SENSE} < 0 \; V, \; see \ Figure \ 11 \end{array} $		-0.1		μA
			$ \begin{array}{l} R_{THR} = 0 \; \Omega, \; R_{SENSE} = 562 \; \Omega \pm 1\%; \\ 5 \; V < V_{SENSE} < V_{IL}, \; see \; Figure \; 11 \end{array} $	1.9		2.5	
			$ R_{THR} = 0 \ \Omega, \ R_{SENSE} = 562 \ \Omega \pm 1\%; \\ V_{IL} < V_{SENSE} < 30 \ V, \ see \ Figure \ 11 $	2.05		2.75	m 4
			$ \begin{array}{l} R_{THR} = 0 \; \Omega, \; R_{SENSE} = 562 \; \Omega \pm 1\%; \\ 30 \; V < V_{SENSE} < 36 \; V, \; see \ Figure \ 11 \end{array} $	2.1	2.83	mA	
I _(INx+SENSEx)	Sum of current drawn SENSE pins	from IN and	$ \begin{array}{l} R_{THR} = 0 \; \Omega, \; R_{SENSE} = 562 \; \Omega \pm 1\%; \\ 36 \; V < V_{SENSE} < 60 \; V^{(1)}, \; see \ Figure \ 11 \end{array} $	2.1	2.1		
			$ R_{\text{THR}} = 0 \ \Omega, \ R_{\text{SENSE}} = 200 \ \Omega \pm 1\%; $	-0.1			μA
			$ \begin{array}{l} R_{THR} = 0 \; \Omega, \; R_{SENSE} = 200 \; \Omega \pm 1\%; \\ 5 \; V < V_{SENSE} < V_{IL}, \; see \ Figure \ 11 \end{array} $	5.3		6.8	
			$ \begin{array}{l} R_{THR} = 0 \; \Omega, \; R_{SENSE} = 200 \; \Omega \pm 1\%; \\ V_{IL} < V_{SENSE} < 36 \; V^{(1)}, \; see \ Figure \ 11 \end{array} $	5.5		7	mA
			$R_{THR} = 0 \Omega, R_{SENSE} = 200 \Omega \pm 1\%;$ 36 V < V _{SENSE} < 60 V ⁽¹⁾ , see Figure 11	5.5		7.3	

(1) See the *Thermal Considerations* section.

Electrical Characteristics—DC Specification (continued)

(Over recommended operating conditions unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
VOLTAG	E TRANSITION THRESHOLD ON FIELD SID	DE				
		R_{SENSE} = 562 Ω , R_{THR} = 0 Ω , see Figure 11	6.5	7		
V _{IL}	Low level threshold voltage at module input (including RTup) for output high	R_{SENSE} = 562 Ω , R_{THR} = 1 k Ω , see Figure 11	8.7	9.2		V
		R_{SENSE} = 562 Ω , R_{THR} = 4 k Ω , see Figure 11	15.2	15.8		
		R_{SENSE} = 562 Ω , R_{THR} = 0 Ω , see Figure 11		8.2	8.55	
VIH	High level threshold voltage at module input (including R _{TUP}) for output low	R_{SENSE} = 562 Ω , R_{THR} = 1 k Ω , see Figure 11		10.4	10.95	V
		R_{SENSE} = 562 Ω , R_{THR} = 4 k Ω , see Figure 11		17	18.25	
		R_{SENSE} = 562 Ω , R_{THR} = 0 Ω , see Figure 11	1	1.2		
V _{HYS}	Threshold voltage hysteresis at module	R_{SENSE} = 562 Ω , R_{THR} = 1 k Ω , see Figure 11	1	1.2		V
	bar	$R_{SENSE} = 562 \ \Omega, R_{THR} = 4 \ k\Omega$, see Figure 11	1	1.2		

6.10 Switching Characteristics—AC Specification

(Over recommended operating conditions unless otherwise noted).

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _r , t _f	Output signal rise and fall time, OUTx pins	Input rise and fall times = 10 ns, see Figure 10		3		ns
t _{PLH}	Propagation delay time for low to high transition	Input rise and fall times = 10 ns, see Figure 10		110	140	ns
t _{PHL}	Propagation delay time for high to low transition	Input rise and fall times = 10 ns, see Figure 10		10	15	ns
t _{sk(p)}	Pulse skew t _{PHL} - t _{PLH}	Input rise and fall times = 10 ns, see Figure 10		102	130	ns
t _{UI}	Minimum pulse width	Input rise and fall times = 125 ns, see Figure 10	150			ns
t _{PHZ}	Disable propagation delay, high- to-high impedance output	See Figure 13		17	40	ns
t _{PLZ}	Disable propagation delay, low- to-high impedance output	See Figure 12		17	40	ns
t _{PZH}	Enable propagation delay, high impedance-to-high output	See Figure 13		3	8.5	μs
t _{PZL}	Enable propagation delay, high impedance-to-low output	See Figure 12		17	40	ns
СМТІ	Common mode transient immunity	See Figure 14	25	70		kV/µs

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6.11 Insulation Characteristics Curves





6.12 Typical Characteristics





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7 Parameter Measurement Information

7.1 Test Circuits



Figure 10. Switching Characteristics Test Circuit and Voltage Waveforms







Test Circuits (continued)



Figure 12. Enable and Disable Propagation Delay Time Test Circuit and Waveform—Logic Low State

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Test Circuits (continued)



Figure 13. Enable and Disable Propagation Delay Time Test Circuit and Waveform—Logic High State



(1) Pass Criterion: The output must remain stable.

Figure 14. Common-Mode Transient Immunity Test Circuit



8 Detailed Description

8.1 Overview

The ISO1211 and ISO1212 devices are fully-integrated, isolated digital-input receivers with IEC 61131-2 Type 1, 2, and 3 characteristics. The devices receive 24-V to 60-V digital-input signals and provide isolated digital outputs. No field-side power supply is required. An external resistor, R_{SENSE}, on the input-signal path precisely sets the limit for the current drawn from the field input based on an internal feedback loop. The voltage transition thresholds are compliant with Type 1, 2, and 3 and can be increased further using an external resistor, R_{THR}. For more information on selecting the R_{SENSE} and R_{THR} resistor values, see the *Detailed Design Procedure* section. The ISO121x devices use an ON-OFF keying (OOK) modulation scheme to transmit the digital data across a silicon-dioxide based isolation barrier. The transmitter sends a high frequency carrier across the barrier to represent one digital state and sends no signal to represent the other digital state. The receiver demodulates the signal after advanced signal conditioning and produces the output through a buffer stage. The conceptual block diagram of the ISO121x device is shown in the *Functional Block Diagram* section.

8.2 Functional Block Diagram



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8.3 Feature Description

The ISO121x devices receive 24-V to 60-V digital input signals and provide isolated digital outputs. An external resistor, R_{SENSE}, connected between the INx and SENSEx pins, sets the limit for the current drawn from the field input. Internal voltage comparators connected to the SENSEx pins determine the input-voltage transition thresholds.

The output buffers on the control side are capable of providing enough current to drive status LEDs. The EN pin is used to enable the output buffers. A low state on the EN pin puts the output buffers in a high-impedance state.

The ISO121x devices are capable of operating up to 4 Mbps. Both devices support an isolation withstand voltage of 2500 V_{RMS} between side 1 and side 2. Table 1 provides an overview of the device features.

PART NUMBER	CHANNELS	MAXIMUM DATA RATE	PACKAGE	RATED ISOLATION								
ISO1211	1	4 Mbps	8-pin SOIC (D)	2500 V _{RMS} , 3600 V _{PK}								
ISO1212	2	4 Mbps	16-pin SSOP (DBQ)	2500 V _{RMS} , 3600 V _{PK}								

Table 1. Device Features

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8.4 Device Functional Modes

Table 2 lists the functional modes for the ISO121x devices.

SIDE 1 SUPPLY V _{CC1}	INPUT (INx, SENSEx)	OUTPUT ENABLE (EN)	OUTPUT (OUTx)	COMMENTS								
	Н	H or Open	Н	Channel output assumes the logic state of channel								
PU	L	H or Open	L	input.								
	Open	H or Open	L	When INx and SENSEx are open, the output of the corresponding channel goes to Low.								
	х	L	Z	A low value of output enable causes the outputs to be high impedance.								
PD	х	х	Undetermined	When V_{CC1} is unpowered, a channel output is undetermined ⁽²⁾ . When V_{CC1} transitions from unpowered to powered up; a channel output assumes the logic state of the input.								

Table 2. Function Table⁽¹⁾

V_{CC1} = Side 1 power supply; PU = Powered up (V_{CC1} ≥ 2.25 V); PD = Powered down (V_{CC1} ≤ 1.7 V); X = Irrelevant; H = High level; L = Low level; Z = High impedance
 The outputs are in an undetermined state when 1.7 V < V_{CC1} < 2.25 V.



9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The ISO1211 and ISO1212 devices are fully-integrated, isolated digital-input receivers with IEC 61131-2 Type 1, 2, and 3 characteristics. These devices are suitable for high-channel density, digital-input modules for programmable logic controllers and motor control digital input modules. The devices receive 24-V to 60-V digital-input signals and provide isolated digital outputs. No field side power supply is required. An external resistor, R_{SENSE} , on the input signal path precisely sets the limit for the current drawn from the field input. This current limit helps minimize power dissipated in the system. The current limit can be set for Type 1, 2, or 3 operation. The voltage transition thresholds are compliant with Type 1, 2, and 3 and can be increased further using an external resistor, R_{THR} . For more information on selecting the R_{SENSE} and R_{THR} resistor values, see the *Detailed Design Procedure* section. The ISO1211 and ISO1212 devices are capable of high speed operation and can pass through a minimum pulse width of 150 ns. The ISO1211 device has a single receive channel. The ISO1212 device has two receive channels that are independent on the field side.



Figure 15. Switching Characteristics for IEC61131-2 Type 1, 2, and 3 Proximity Switches

9.2 Typical Application

9.2.1 Sinking Inputs

Figure 16 shows the design for a typical multichannel, isolated digital-input module with sinking inputs. Pushbutton switches, proximity sensors, and other field inputs connect to the host controller through an isolated interface. The design is easily scalable from a few channels, such as 4 or 8, to many channels, such as 256 or more. The R_{SENSE} resistor limits the current drawn from the input pins. The R_{THR} resistor is used to adjust the voltage thresholds and limit the peak current during surge events. The C_{IN} capacitor is used to filter noise on the input pins. For more information on selecting R_{SENSE} , R_{THR} , and C_{IN} , see the *Detailed Design Procedure* section.

The ISO121x devices derive field-side power from the input pins which eliminates the requirement for a fieldside, 24-V input power supply to the module. Similarly, an isolated dc-dc converter creating a field-side power supply from the controller side back plane supply is also eliminated which improves flexibility of system design and reduces system cost.

For systems requiring channel-to-channel isolation on the field side, use the ISO1211 device as shown in Figure 17.

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Typical Application (continued)



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Figure 16. Typical Application Schematic With Sinking Inputs



Typical Application (continued)



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Figure 17. Single-Channel or Channel-to-Channel Isolated Designs With ISO1211

9.2.1.1 Design Requirements

The ISO121x devices require two resistors, R_{THR} and R_{SENSE} , and a capacitor, C_{IN} , on the field side. For more information on selecting R_{SENSE} , R_{THR} , and C_{IN} , see the *Detailed Design Procedure* section. A 100-nF decoupling capacitor is required on V_{CC1}.

9.2.1.2 Detailed Design Procedure

9.2.1.2.1 Setting Current Limit and Voltage Thresholds

The R_{SENSE} resistor limits the current drawn from the field input. A value of 562 Ω for R_{SENSE} is recommended for Type 1 and Type 3 operation, and results in a current limit of 2.25 mA (typical). A value of 200 Ω for R_{SENSE} is recommended for Type 2 operation, and results in a current limit of 6 mA (typical). In each case, a (slightly) lower value of R_{SENSE} can be selected based on the need for a higher current limit or component availability. For more information, see the *Electrical Characteristics—DC Specification* table and *Typical Characteristics* section. A 1% tolerance is recommended on R_{SENSE} but 5% resistors can also be used if higher variation in the current limit value is acceptable. The relationship between the R_{SENSE} resistor and the typical current limit (I_L) is given by Equation 1.

$$I_{L} = \frac{2.25 \text{ mA} \times 562 \Omega}{R_{\text{SENSE}}}$$
(1)

The R_{THR} resistor sets the voltage thresholds (V_{IH} and V_{IH}) as well as limits the surge current. A value of 1 k Ω is recommended for R_{THR} in Type 3 systems (maximum threshold voltage required is 11 V). A value of 2.5 k Ω is recommended for R_{THR} in Type 1 systems (maximum threshold voltage required is 15 V) and a value of 330 Ω is recommended for R_{THR} in Type 2 systems. The *Electrical Characteristics*—*DC Specification* table lists and the *Typical Characteristics* section describes the voltage thresholds with different values of R_{THR}. For other values of R_{THR}, derive the values through linear interpolation. Use Equation 2 and Equation 3 to calculate the values for the typical V_{IH} values and minimum V_{IL} values, respectively.

$$V_{\text{IH}} \text{ (typ)} = 8.25 \text{ V} + \text{R}_{\text{THR}} \times \frac{2.25 \text{ mA} \times 562 \Omega}{\text{R}_{\text{SENSE}}}$$

(2)

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9.2.1.2.2 Thermal Considerations

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Typical Application (continued)

$$V_{\text{IL}} (\text{min}) = 7.1 \text{ V} + \text{R}_{\text{THR}} \times \frac{2.25 \text{ mA} \times 562 \Omega}{\text{R}_{\text{SENSE}}}$$
(3)

The maximum voltage on the SENSE pins of the ISO121x device is 60 V. However, because the R_{THR} resistor drops additional voltage, the maximum voltage supported at the module inputs is higher and given by Equation 4.

$$V_{\text{IN}} \text{ (max)} = 60 \text{ V} + \text{R}_{\text{THR}} \times \frac{2.1 \text{ mA} \times 562 \Omega}{\text{R}_{\text{SENSE}}}$$

A value of 0 Ω for R_{THR} also meets Type 1, Type 2 and Type 3 voltage-threshold requirements. The value of R_{THR} should be maximized for best EMC performance while meeting the desired input voltage thresholds. Because R_{THR} is used to limit surge current, 0.25 W MELF resistors must be used.

Figure 18 shows the typical input current characteristics and voltage transition thresholds for 562- Ω R_{SENSE} and 1-kΩ R_{THR} .

Figure 18. Transition Thresholds

Thermal considerations constrain operation at different input current and voltage levels. The power dissipated inside the ISO121x devices is determined by the voltage at the SENSE pin (V_{SENSE}) and the current drawn by the device (I(INX+SENSEX)). The internal power dissipated, when taken with the junction-to-air thermal resistance defined in the Thermal Information table can be used to determine the junction temperature for a given ambient temperature. The junction temperature must not exceed 150°C.

Figure 19 shows the maximum allowed ambient temperature for the ISO1211 device for different current limit and input voltage conditions. The ISO1211 device can be used with a V_{SENSE} voltage up to 60 V and an ambient temperature of up to 125°C for an R_{SENSE} value of 562 Ω, which corresponds to a typical current limit of 2.25 mA. At higher levels of current limit, either the ambient temperature or the maximum value of the V_{SENSE} voltage must be derated. In any design, the voltage drop across the external series resistor, R_{THR}, reduces the maximum voltage received by the SENSE pin and helps extend the allowable module input voltage and ambient temperature range.



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(4)



Typical Application (continued)



(1) This figure also applies to the ISO1212 device if only one of the two channels are expected to be active at a given time.

Figure 19. Maximum Ambient Temperature Derating Curve for ISO1211 vs V_{SENSE}

Figure 20 shows the maximum allowed ambient temperature for the ISO1212 device for different current limit and input voltage conditions. The ISO1212 device can be used with a V_{SENSE} voltage up to 36 V and an ambient temperature of up to 125°C for an R_{SENSE} value of 562 Ω , which corresponds to a typical current limit of 2.25 mA. At higher current limit levels, either the ambient temperature or the maximum value of the V_{SENSE} voltage must be derated. Operation of the ISO1212 device with an R_{SENSE} value of 200 Ω and with both channels active is not recommended beyond a V_{SENSE} voltage of 36 V. In any design, the voltage drop across the series resistor, R_{THR} , reduces the maximum voltage received by the SENSE pin and helps extend the allowable module input voltage and ambient temperature range.



(1) This figure only applies if both channels of the ISO1212 device are expected to be on at the same time. If only one channel is expected to be on at a given time, refer to Figure 19.

Figure 20. Maximum Ambient Temperature Derating Curve for ISO1212 vs V_{SENSE}



Typical Application (continued)

9.2.1.2.3 Designing for 48-V Systems

The ISO121x devices are suitable for 48-V digital input receivers. The current limit, voltage transition thresholds, and maximum voltage supported at the module input are governed by Equation 1, Equation 2, Equation 3, and Equation 4. For 48-V systems, a threshold voltage close to 25 V is desirable. The R_{THR} resistor can be adjusted to achieve this higher threshold. For example, with an R_{SENSE} value of 562 Ω and an R_{THR} value of 7.5 k Ω , a V_{IH} value of approximately 25 V can be achieved. With this setting, the R_{THR} resistor drops a voltage of approximately 17 V, reducing the maximum value of the V_{SENSE} voltage for any given module input voltage. This drop vastly increases the allowable module input voltage and ambient temperature range as discussed in *Thermal Considerations*.

9.2.1.2.4 Surge, ESD, and EFT Tests

Digital input modules are subject to surge (IEC 61000-4-5), electrostatic discharge or ESD (IEC 61000-4-2) and electrical fast transient or EFT (IEC 61000-4-4) tests. The surge impulse waveform has the highest energy and the widest pulse width, and is therefore the most stringent test of the three.

Figure 16 shows the application diagram for Type 1 and 3 systems. For a 1-kV_{PP} surge test between the input terminals and protection earth (PE), a value of 1 k Ω for R_{THR} and 10 nF for C_{IN} is recommended. Table 3 lists a summary of recommended component values to meet different levels of EMC requirements for Type 1 and 3 systems.

IEC 61131-2 TYPE			C _{IN}		SURGE			
	R _{SENSE}	R _{TH}		LINE-TO-PE	LINE-TO-LINE	LINE-TO- FGND	IEC ESD	IEC EFT
Type 1	562	3 kΩ	10 nF	±1 kV	±1 kV	±1 kV	±6 kV	±4 kV
Туре 3	562	1 10	10 nF	±1 kV	±1 kV	±500 V	±6 kV	±4 kV
		1 K22	330 nF	±1 kV	±1 kV	±1 kV	±6 kV	±4 kV

Table 3. Surge, IEC ESD and EFT

Figure 21 shows the test setup and application circuit used for surge testing. A noise filtering capacitor of 500 pF is recommended between the FGND pin and PE (earth). The total value of effective capacitance between the FGND pin and any other ground potential (including PE) must not exceed 500 pF for optimum surge performance. For line-to-PE test (common-mode test), the FGND pin is connected to the auxiliary equipment (AE) through a decoupling network.





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- (1) For line-to-PE test, FGND is connected to the auxiliary equipment (AE) through a decoupling network.
- (2) A noise filtering capacitor of about 500 pF is recommended between the FGND pin and PE (earth). The total value of effective capacitance between the FGND pin and any other ground potential (including PE) must not exceed 500 pF for optimum performance.

Figure 21. Setup and Application Circuit Used for Surge Test

For higher voltage levels of surge tests or for faster systems that cannot use a large value for C_{IN} , TVS diodes or varistors can be used to meet EMC requirements. Type 2 systems that use a smaller value for R_{THR} may also require TVS diodes or varistors for surge protection. Figure 22 shows an example usage of TVS diodes for surge protection. The recommended components for surge protection are VCAN26A2-03S (TVS, Vishay), EZJ-P0V420WM (Varistor, Panasonic), and GSOT36C (TVS, Vishay).

Use of the R_{THR} resistor also reduces the peak current requirement for the TVS diodes, making them smaller and cost effective. For example, a 2-kV surge through a 1-k Ω R_{THR} resistor creates only 2-A peak current. Also, because of voltage drop across the R_{THR} resistor in normal operation, the working voltage requirement for the varistor or TVS diodes is reduced. For example, for a R_{THR} value of 1 k Ω and an R_{SENSE} value of 562 Ω , a module designed for 30-V inputs only requires 28-V TVS diodes because the R_{THR} resistor drops more than 2 V.

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Figure 22. TVS Diodes Used Instead of a Filtering Capacitor for Surge Protection in Faster Systems

9.2.1.2.5 Multiplexing the Interface to the Host Controller

The ISO121x devices provide an output-enable pin on the controller side (EN). Setting the EN pin to 0 causes the output buffers to be in the high-impedance state. This feature can be used to multiplex the outputs of multiple ISO121x devices on the same host-controller input, reducing the number of pins on the host controller.

In the example shown in Figure 23, two sets of 8-channel inputs are multiplexed, reducing the number of input pins required on the controller from 16 to 10. Similarly, if four sets of 8-channel inputs are multiplexed, the number of pins on the controller is reduced from 32 to 12.



Figure 23. Using the Output Enable Option to Multiplex the Interface to the Host Controller

9.2.1.2.6 Status LEDs

The outputs of the ISO121x devices can be used to drive status LEDs on the controller side as shown in Figure 24. The output buffers of the ISO121x can provide 4-mA, 3-mA, and 2-mA currents while working at V_{CC1} values of 5 V, 3.3 V, and 2.5 V respectively.



In some cases, placing the LED on the field side is desirable although it is powered from V_{CC1} . In such cases, the signal carrying current to the LED can be routed in an inner layer without compromising the isolation of the digital-input module. For more information, see the *Layout Guidelines* section.



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Figure 24. Using ISO121x Outputs to Drive Status LEDs

9.2.1.3 Application Curve





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9.2.2 Sourcing Inputs

The ISO121x devices can be configured as sourcing inputs as shown in Figure 26. In this configuration, all the SENSE pins are connected to the common voltage (24 V), and the inputs are connected to the individual FGND pins.



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Figure 26. Typical Application Circuit With Sourcing Inputs



9.2.3 Sourcing and Sinking Inputs

The ISO1212 device can be used to create an input module that can sink and source current as shown in Figure 27. In this configuration, channel 1 is active if the COM terminal is connected to ground for sinking inputs, and channel 2 is active if the COM terminal is connected to 24 V for sourcing input. The digital input is considered high if either the OUT1 or OUT2 pin is high.



Figure 27. Application Circuit—ISO1212 With Sourcing and Sinking Inputs

10 Power Supply Recommendations

To help ensure reliable operation at data rates and supply voltages, a $0.1-\mu$ F bypass capacitor is recommended on the side 1 supply pin (V_{CC1}). The capacitor should be placed as close to the supply pins as possible.

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11 Layout

11.1 Layout Guidelines

The board layout for ISO1211 and ISO1212 can be completed in two layers. On the field side, place R_{SENSE} , C_{IN} , and R_{THR} on the top layer. Use the bottom layer as the field ground (FGND) plane. TI recommends using R_{SENSE} and C_{IN} in 0603 footprint for a compact layout, although larger sizes (0805) can also be used. The C_{IN} capacitor is a 50-V capacitor and is available in the 0603 footprint. Keep C_{IN} as close to the ISO121x device as possible. The SUB pin on the ISO1211 device and the SUB1 and SUB2 pins on the ISO1212 device should be left unconnected. For group isolated design, use vias to connect the FGND pins of the ISO121x device to the bottom FGND plane. The placement of the R_{THR} resistor is flexible, although the resistor pin connected to external high voltage should not be placed within 4 mm of the ISO121x device pins or the C_{IN} and R_{SENSE} pins to avoid flashover during EMC tests.

Only a decoupling capacitor is required on side 1. Place this capacitor on the top-layer, with the bottom layer for GND1.

If a board with more than two layers is used, placing two ISO121x devices on the top-and bottom layers (back-toback) is possible to achieve a more compact board. The inner layers can be used for FGND.

Figure 28 and Figure 29 show the example layouts.

In some designs, placing the LED on the field side is desirable although it is powered from V_{CC1} . In such cases, the signal carrying current to the LED can be routed in an inner layer without compromising the isolation of the digital-input module as shown in Figure 30. The LED must be placed with at least 4-mm spacing between other components and connections on side 1 to ensure adequate isolation.

11.2 Layout Example



Figure 28. Layout Example With ISO1211



Layout Example (continued)



Figure 29. Layout Example With ISO1212



Figure 30. Layout Example With LED Placed on the Field Side But Driven From V_{CC1} Power Domain

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12 Device and Documentation Support

12.1 Documentation Support

12.1.1 Related Documentation

For related documentation see the following:

- Texas Instruments, How To Simplify Isolated 24-V PLC Digital Input Module Designs TI TechNote
- Texas Instruments, *Isolation Glossary*
- Texas Instruments, ISO1211 Isolated Digital-Input Receiver Evaluation Module user's guide
- Texas Instruments, ISO1212 Isolated Digital-Input Receiver Evaluation Module user's guide

12.2 Related Links

The table below lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to order now.

PARTS	PARTS PRODUCT FOLDER		TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY							
ISO1211	Click here	Click here	Click here	Click here	Click here							
ISO1212	Click here	Click here	Click here	Click here	Click here							

Table 4. Related Links

12.3 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

12.4 Community Resource

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

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Design Support TI's Design Support Quickly find helpful E2E forums along with design support tools and contact information for technical support.

12.5 Trademarks

E2E is a trademark of Texas Instruments. All other trademarks are the property of their respective owners.

12.6 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

12.7 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.



13 Mechanical, Packaging, and Orderable Information

The following pages include mechanical packaging and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package	Pins	Package	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
ISO1211D	ACTIVE	SOIC	D	8	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-55 to 125	1211	Samples
ISO1211DR	ACTIVE	SOIC	D	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-55 to 125	1211	Samples
ISO1212DBQ	ACTIVE	SSOP	DBQ	16	75	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-55 to 125	1212	Samples
ISO1212DBQR	ACTIVE	SSOP	DBQ	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-55 to 125	1212	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

⁽⁵⁾ Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

⁽⁶⁾ Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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PACKAGE MATERIALS INFORMATION

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TAPE AND REEL INFORMATION





QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal												
Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
ISO1211DR	SOIC	D	8	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1
ISO1212DBQR	SSOP	DBQ	16	2500	330.0	12.4	6.4	5.2	2.1	8.0	12.0	Q1

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PACKAGE MATERIALS INFORMATION

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
ISO1211DR	SOIC	D	8	2500	367.0	367.0	38.0
ISO1212DBQR	SSOP	DBQ	16	2500	367.0	367.0	38.0

D (R-PDSO-G8)

PLASTIC SMALL OUTLINE



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
- E. Reference JEDEC MS-012 variation AA.



GENERIC PACKAGE VIEW

SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE



Images above are just a representation of the package family, actual package may vary. Refer to the product data sheet for package details.



DBQ0016A



PACKAGE OUTLINE

SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE



NOTES:

1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.

- 2. This drawing is subject to change without notice.
- 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 inch, per side.
- This dimension does not include interlead flash.
 Reference JEDEC registration MO-137, variation AB.



DBQ0016A

EXAMPLE BOARD LAYOUT

SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



DBQ0016A

EXAMPLE STENCIL DESIGN

SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE



NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

9. Board assembly site may have different recommendations for stencil design.



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